

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:)	
)	
Young-Joo KIM)	
)	
Application No.: Unassigned)	Group Art Unit: Unassigned
)	
Filed: November 21, 2003)	Examiner: Unassigned

For: METHOD OF CRYSTALLIZING AMORPHOUS SILICON AND
DEVICE FABRICATED USING THE SAME

Commissioner for Patents
MAIL STOP PATENT APPLICATION

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)

Pursuant to 37 C.F.R. §§ 1.56 and 1.97(b), Applicant brings to the attention of the Examiner the documents listed on the attached PTO-1449. This Information Disclosure Statement is being filed within three months of the filing date of the above-referenced application.

A copy of each listed document is attached.

This submission does not represent that a search has been made or that no better art exists and does not constitute an admission that the listed document is material or constitutes "prior art." If it should be determined that the listed document does not constitute "prior art" under United States law, Applicants reserve the right to present to the Office the relevant facts and law regarding the appropriate status of such document. Applicants further reserve the right to take appropriate action to establish the patentability of the disclosed invention over the listed document, should the document be applied against the claims of the present application.

If there is any fee due in connection with the filing of this Statement, please charge the fee to our Deposit Account No. 50-0310.

Respectfully submitted,

MORGAN, LEWIS & BOCKIUS LLP



Robert J. Goodell, Reg. No. 41,040

Date: November 21, 2003

MORGAN, LEWIS & BOCKIUS LLP
1111 Pennsylvania Avenue, N.W.
Washington, D.C. 20004
(202) 739-3000

INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)	Attorney Docket No. 053785-5157	Serial No. Unassigned
PTO Form 1449	Applicants Young-Joo KIM	Filing Date November 21, 2003
		Group Unassigned

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

H. IKEDA. "Evaluation of Grain Boundary Trap States in Polycrystalline-Silicon Thin-Film Transistors by Mobility and Capacitance Measurements." Journal of Applied Physics. Vol. 91, No. 7, April 2002, pp. 4637-4645.

Examiner _____ Date Considered _____
Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.